ALPHA & OMEGA SEMICONDUCTOR

AO4427

P-Channel Enhancement Mode Field Effect Transistor

General Description

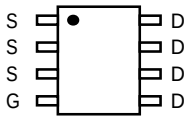
The AO4427/L uses advanced trench technology to provide excellent $R_{DS(ON)}$, and ultra-low low gate charge with a 25V gate rating. This device is suitable for use as a load switch or in PWM applications. The device is ESD protected.
AO4427 and AO4427L are electrically identical.
-RoHS Compliant
-AO4427L is Halogen Free

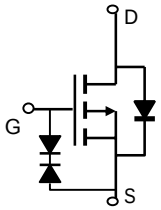
Features

V_{DS} (V) = -30V
I_D = -12.5 A (V_{GS} = -20V)
$R_{DS(ON)}$ < 12mΩ (V_{GS} = -20V)
$R_{DS(ON)}$ < 14mΩ (V_{GS} = -10V)
ESD Rating: 2KV HBM

Ciss,Coss,Crss Tested

SOIC-8
Top View





Absolute Maximum Ratings T_A=25°C unless otherwise noted

Parameter		Symbol	Maximum	Units
Drain-Source Voltage		V_{DS}	-30	V
Gate-Source Voltage		V_{GS}	±25	V
Continuous Drain Current [AF]	T_A=25°C	I_D	-12.5	A
	T_A=70°C		-10.5	
Pulsed Drain Current [B]		I_{DM}	-60	
Power Dissipation [A]	T_A=25°C	P_D	3	W
	T_A=70°C		2.1	
Junction and Storage Temperature Range		T_J, T_{STG}	-55 to 150	°C

Thermal Characteristics

Parameter		Symbol	Typ	Max	Units
Maximum Junction-to-Ambient [AF]	t ≤ 10s	$R_{\theta JA}$	28	40	°C/W
Maximum Junction-to-Ambient [A]	Steady-State		54	75	°C/W
Maximum Junction-to-Lead [C]	Steady-State	$R_{\theta JL}$	21	30	°C/W

Electrical Characteristics (T_J=25°C unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	I_D=-250µA, V_{GS}=0V	-30			V
I_{DSS}	Zero Gate Voltage Drain Current	V_{DS}=-30V, V_{GS}=0V			-1	µA
		T_J=55°C			-5	
I_{GSS}	Gate-Body leakage current	V_{DS}=0V, V_{GS}=±25V			±10	µA
$V_{GS(th)}$	Gate Threshold Voltage	V_{DS}=V_{GS} I_D=-250µA	-1.7	-2.5	-3	V
$I_{D(ON)}$	On state drain current	V_{GS}=-10V, V_{DS}=-5V	-60			A
$R_{DS(ON)}$	Static Drain-Source On-Resistance	V_{GS}=-20V, I_D=-12.5A		9.4	12	mΩ
		T_J=125°C		12.2	15	
		V_{GS}=-10V, I_D=-10A		11.5	14	mΩ
		V_{GS}=-4.5V, I_D=-5A		32		mΩ
g_{FS}	Forward Transconductance	V_{DS}=-5V, I_D=-12.5A		24		S
V_{SD}	Diode Forward Voltage	I_S=-1A,V_{GS}=0V			-1	V
I_S	Maximum Body-Diode Continuous Current				-4.2	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	V_{GS}=0V, V_{DS}=-15V, f=1MHz		2330	2900	pF
C_{oss}	Output Capacitance			480		pF
C_{rss}	Reverse Transfer Capacitance			320	448	pF
R_g	Gate resistance	V_{GS}=0V, V_{DS}=0V, f=1MHz	3.4	6.8	10	Ω
SWITCHING PARAMETERS						
Q_g	Total Gate Charge	V_{GS}=-10V, V_{DS}=-15V, I_D=-12.5A		41	52	nC
Q_{gs}	Gate Source Charge			10		nC
Q_{gd}	Gate Drain Charge			12		nC
$t_{D(on)}$	Turn-On DelayTime	V_{GS}=-10V, V_{DS}=-15V, R_L=1.2Ω, R_{GEN}=3Ω		12.8		ns
t_r	Turn-On Rise Time			10.3		ns
$t_{D(off)}$	Turn-Off DelayTime			49.5		ns
t_f	Turn-Off Fall Time			29		ns
t_{rr}	Body Diode Reverse Recovery Time	I_F=-12.5A, dI/dt=100A/µs		28	35	ns
Q_{rr}	Body Diode Reverse Recovery Charge	I_F=-12.5A, dI/dt=100A/µs		20		nC

A: The value of $R_{\theta JA}$ is measured with the device mounted on 1in 2 FR-4 board with 2oz. Copper, in a still air environment with T_A=25°C. The value in any given application depends on the user's specific board design.

B: Repetitive rating, pulse width limited by junction temperature.

C. The $R_{\theta JA}$ is the sum of the thermal impedence from junction to lead $R_{\theta JL}$ and lead to ambient.

D. The static characteristics in Figures 1 to 6 are obtained using <300µs pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with T_A=25°C. The SOA curve provides a single pulse rating.

F. The current rating is based on the t≤ 10s junction to ambient thermal resistance rating.

Rev7: MAY 2008

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

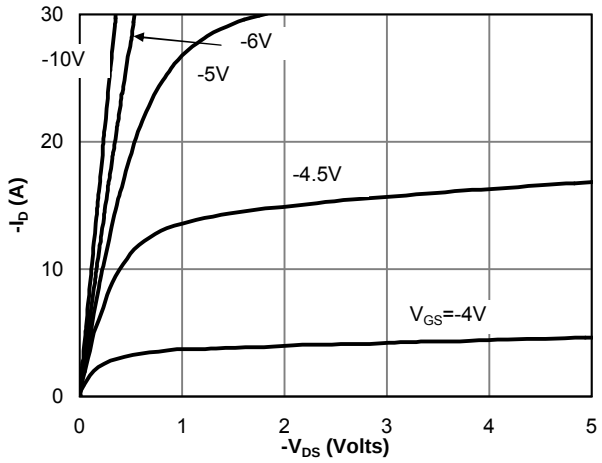


Figure 1: On-Region Characteristics

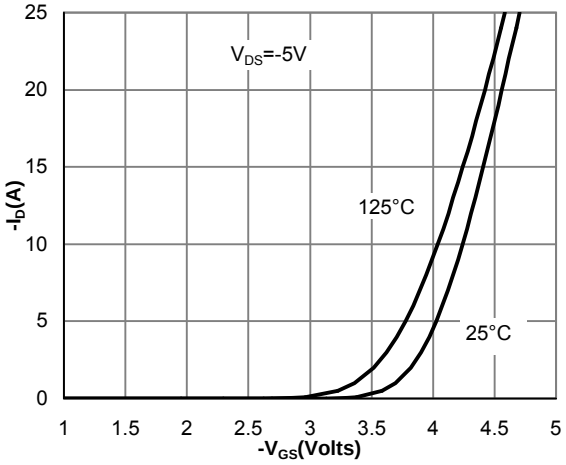


Figure 2: Transfer Characteristics

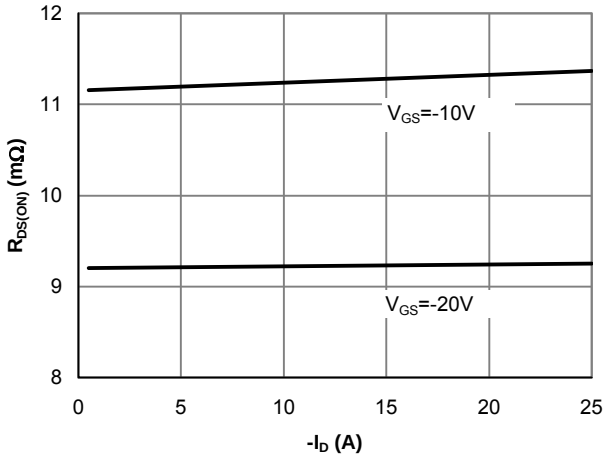


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

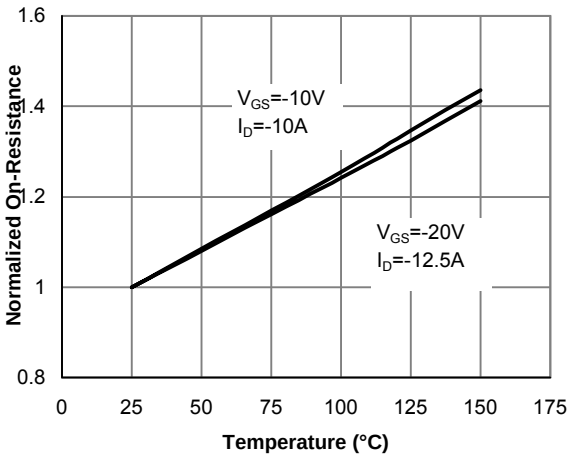


Figure 4: On-Resistance vs. Junction Temperature

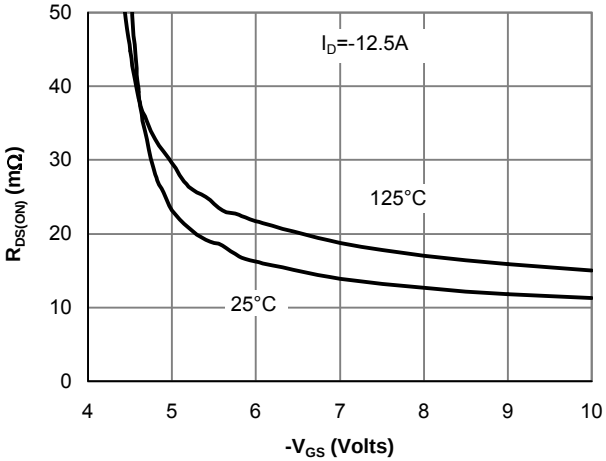


Figure 5: On-Resistance vs. Gate-Source Voltage

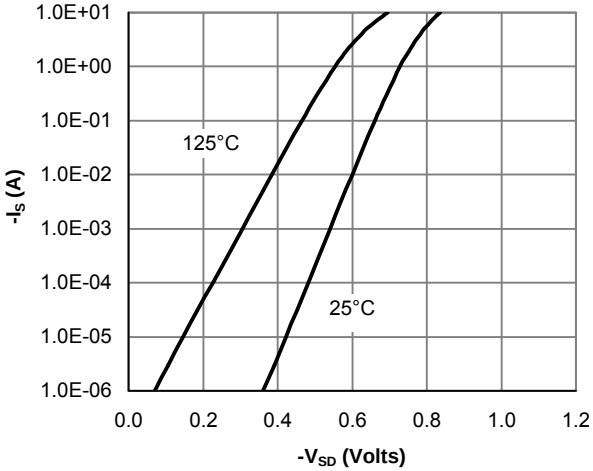


Figure 6: Body-Diode Characteristics

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

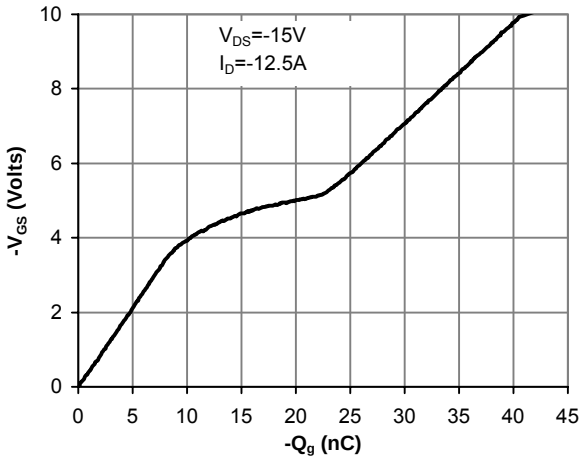


Figure 7: Gate-Charge Characteristics

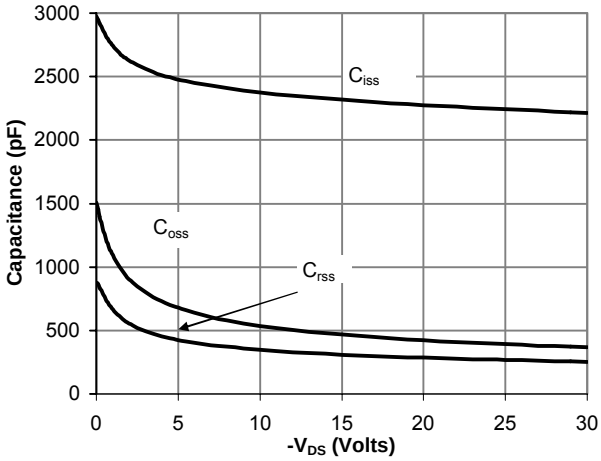


Figure 8: Capacitance Characteristics

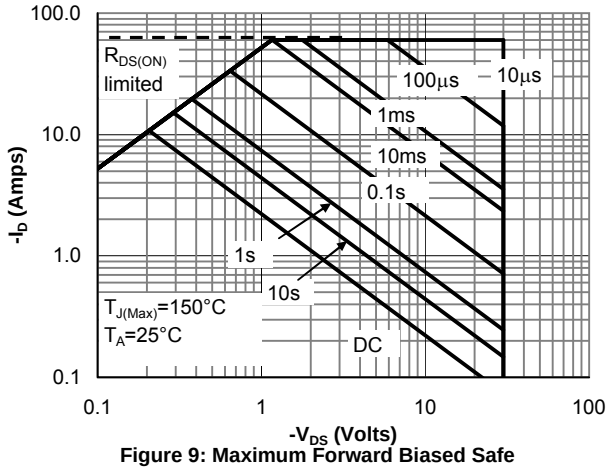


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

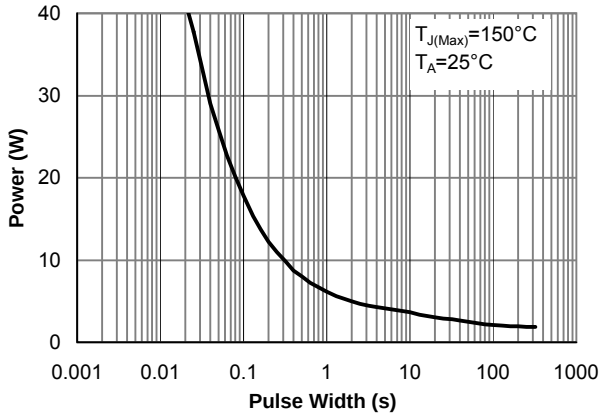


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

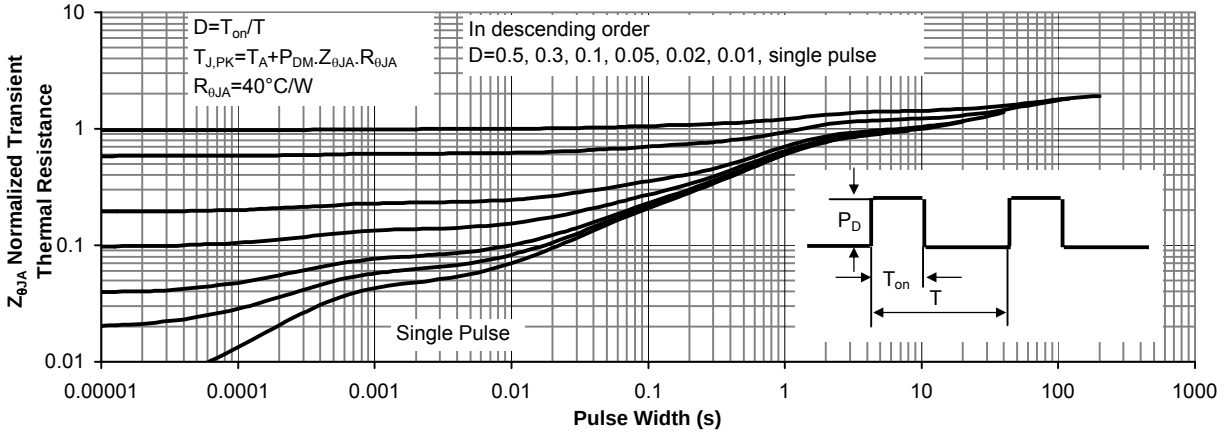


Figure 11: Normalized Maximum Transient Thermal Impedance